

### 60mΩ, 1200V, Silicon Carbide N-Channel Power MOSFET

## **Description**

The LXP SEMI LX2C060N120BY silicon carbide Power MOSFET device has been developed using LXP's advanced and innovative 2nd generation SiC MOSFET technology. The device features a very low R<sub>DS(on)</sub> over the entire temperature range combined with low capacitances and good switching performance, which improve application performance in frequency, energy efficiency, system size and weight reduction.

## **Key Features**

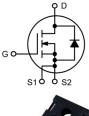
- Typ.  $R_{DS(on)} = 60 \text{m}\Omega$  @  $V_{GS} = 18V$
- · High speed switching performances
- · Low Switching Losses
- 100% Avalanche Tested
- EMI Improved Design
- · Very fast and robust intrinsic body diode

## **Applications**

- DC/DC converter for EV/HEV
- On board charger (OBC)
- · Solar Inverters
- · Energy Storage Systems
- SMPS (Switch Mode Power Supplies)

## **Key performance**

Parameter	Value	Unit
V <sub>DS</sub> (T <sub>j</sub> =25°C)	1200	V
$R_{DS(on),\ typ(T_j=25^{\circ}C,\ I_D=15A,\ V_{GS}=18V)}$	60	mΩ
I <sub>D(Tj=25°C)</sub>	35	А
T <sub>j, max</sub>	175	°C





TO-247-4





## Package Feature

Order code	Marking	Package	Packing
LX2C060N120BY	LX2C060N120B	TO-247-4PIN	Tube



#### **1.Maximum Ratings** (T<sub>j</sub>=25°C unless otherwise specified)

Para	Symbol	Rating	Unit			
Drain-Source Voltage		V <sub>DSS</sub>	1200	V		
Gate-Source Voltage	Gate-Source Voltage		-10/+22	V		
Gate-Source Voltage Recommended Operation Values		V <sub>GSS</sub>	-5/+18	V		
Gate-Source Transient Voltage (t <sub>p</sub> < 1µs, t ≤ 10 hours)		V <sub>GSS</sub>	-11/+25	V		
Continuous Drain Current	T <sub>C</sub> = 25°C		35	^		
	T <sub>C</sub> = 100°C	I <sub>D</sub>	25	- A		
Pulsed Drain Current (Note 2)		I <sub>DM</sub>	115	А		
Avalanche Energy, Single Pulse (Note 3)		E <sub>AS</sub>	200	mJ		
Avalanche Current, Repetitive (Note 2)		I <sub>AR</sub>	20	А		
Continuous Diode Forward Current		Continuous Diode Forward Current		Is	35	А
Power Dissipation		P <sub>tot</sub>	217	W		
Operating Temperature/ Storage Temperature		TJ	-55~175	°C		

#### Note:

- 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 1mH,  $I_{AS}$  = 20A,  $V_{DD}$  = 120V,  $V_{GS}$  = 18V,  $R_g$  = 25 $\Omega$ , Starting  $T_J$  = 25 $^{\circ}$ C

### 2.Thermal characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-to-case	R <sub>thJC</sub>	0.69	°C/W
Thermal resistance, junction-to-ambient	R <sub>thJA</sub>	48	°C/W

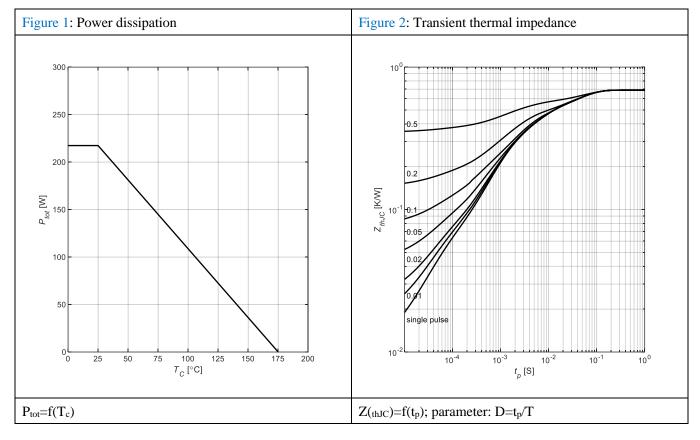


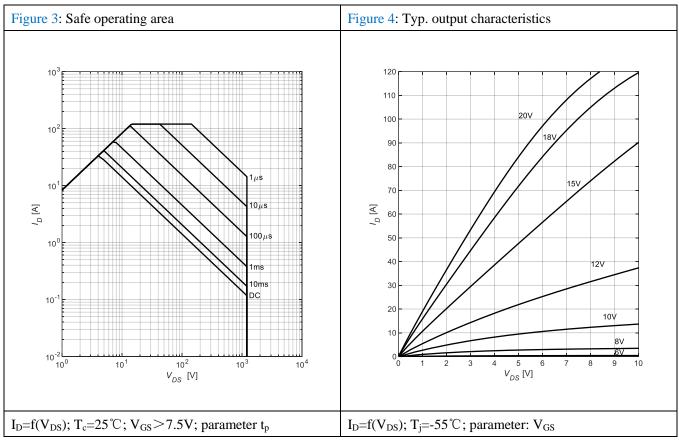
## **3.Electrical Characteristics** (T<sub>j</sub>=25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Statistic Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 100 μA	1200	1600		V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 1200 V, V <sub>GS</sub> = 0 V		1	10	μA
0.1.0	I <sub>GSSF</sub>	V <sub>GS</sub> = 22 V, V <sub>DS</sub> = 0 V			100	nA
Gate-Source Leakage Current	I <sub>GSSR</sub>	V <sub>GS</sub> = -10 V, V <sub>DS</sub> = 0 V			-100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 5$ mA	2.1	2.8	3.5	V
		V <sub>GS</sub> = 18 V, I <sub>D</sub> = 15 A		60	80	
		V <sub>GS</sub> = 18 V, I <sub>D</sub> = 15 A, T <sub>j</sub> =150 °C		90		1
01 11 10 11 10 11 11	_	V <sub>GS</sub> = 18 V, I <sub>D</sub> = 15 A, T <sub>j</sub> =175 °C		100		
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 15 V, I <sub>D</sub> = 15 A		85	110	mΩ
		V <sub>GS</sub> = 15 V, I <sub>D</sub> = 15 A, T <sub>j</sub> =150 °C		110		
		V <sub>GS</sub> = 15 V, I <sub>D</sub> = 15 A, T <sub>j</sub> =175 °C		120		<del>.</del>
Gate Resistance	R <sub>G</sub>	f = 1 MHz,open drain		2		Ω
Dynamic Characteristics						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V		1500		
Output Capacitance	Coss	V <sub>DS</sub> = 800 V		80		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>	f = 1 MHz		7		
Gate to Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> = 800 V		24		
Gate to Drain Charge	Q <sub>gd</sub> V <sub>GS</sub> = -5 to 18 V			19		nC
Gate Charge Total	Qg	I <sub>D</sub> = 15 A		73		1
Switching Characteristic			•		•	
Turn-on delay time	T <sub>d(on)</sub>			9		
Rise time	Tr	]		19		
Turn-off delay time	$T_{d(off)}$	$V_{DD} = 800 \text{ V}, I_D = 15 \text{ A},$		32		ns
Fall time	T <sub>f</sub>	$R_G = 4.7 \Omega$ , $V_{GS} = -5/+18 V$		18		
Turn-on switching energy	Eon	]		140		
Turn-off switching energy	E <sub>off</sub>			40		μJ
Reverse Diode Characteristics			•		•	
D: 1 E 17/16	V <sub>SD</sub>	V <sub>GS</sub> = -5 V, I <sub>SD</sub> = 15 A		4.1		17
Diode Forward Voltage		V <sub>GS</sub> = -5 V, I <sub>SD</sub> = 15 A, Tj=175 °C		3.6		V
Reverse Recovery Time	t <sub>rr</sub>	V 000 V I 45 A		17		ns
Reverse Recovery Charge	Q <sub>rr</sub>	V <sub>R</sub> = 800 V, I <sub>F</sub> = 15 A, di/dt = 1000 A/µs		65		nC
Peak Reverse Recovery Current	I <sub>rrm</sub>	- αι, αι – 1000 Αγμο		10		Α

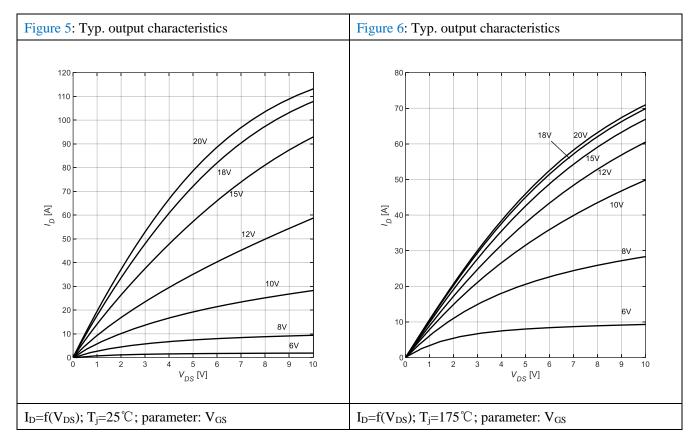


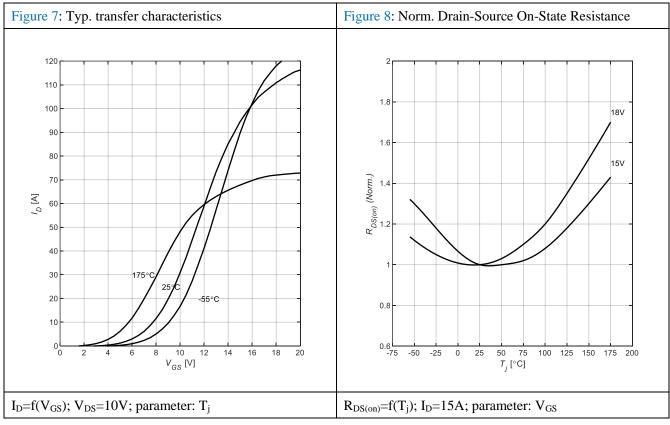
#### 4. Electrical characteristic curves



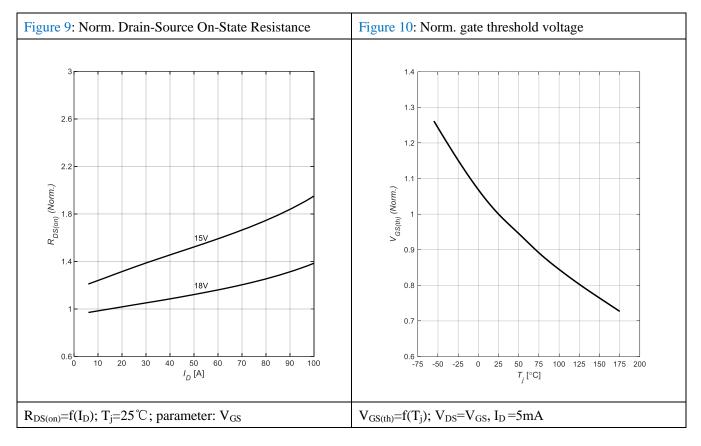


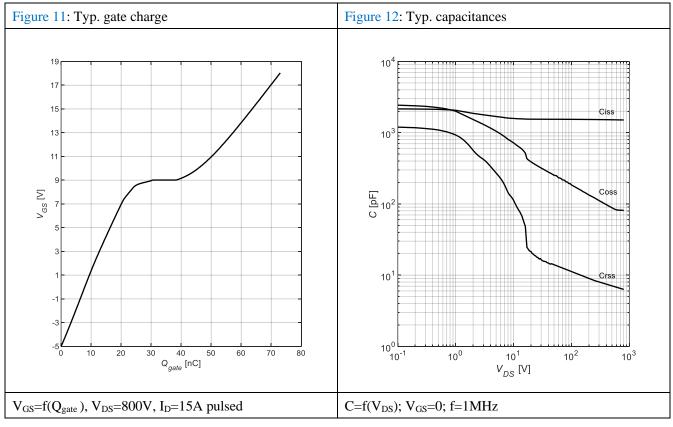




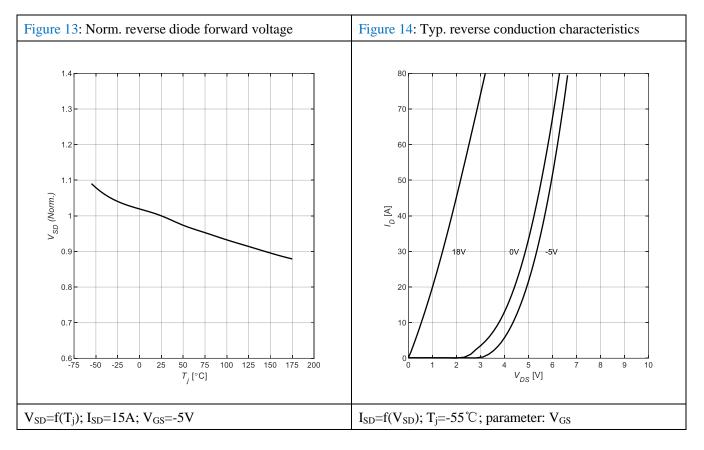


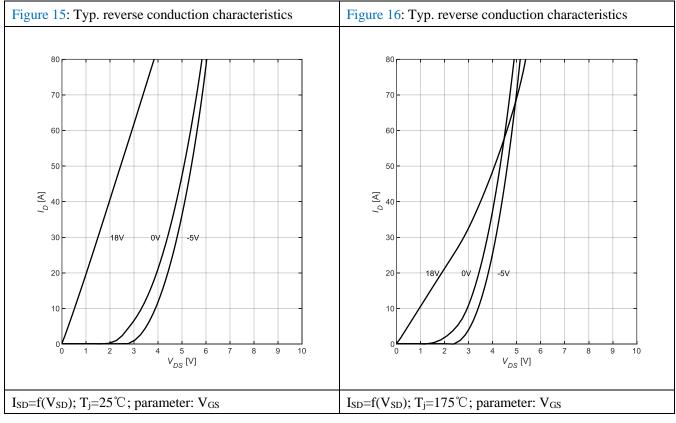




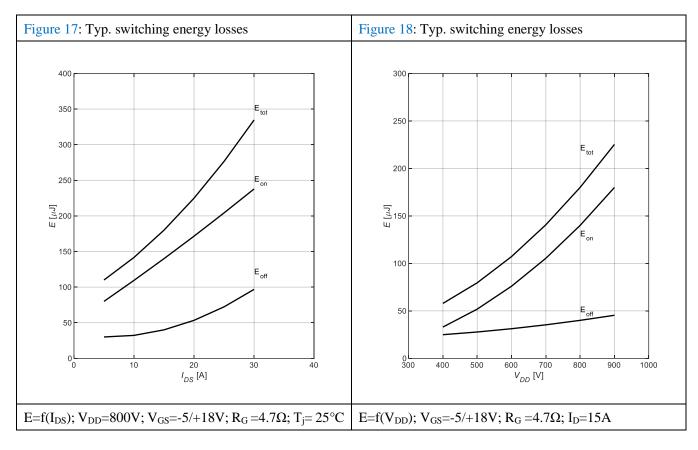


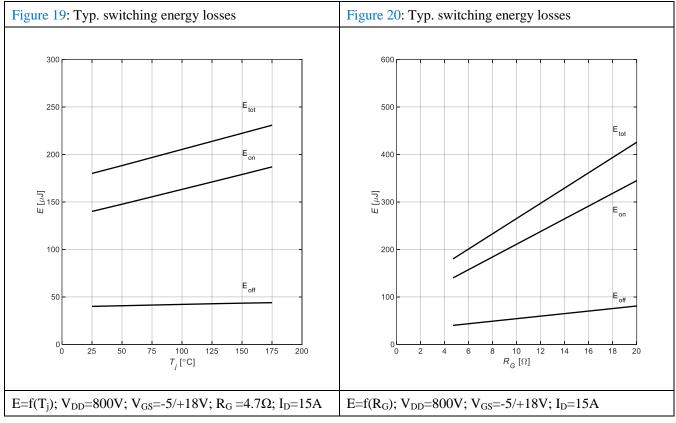








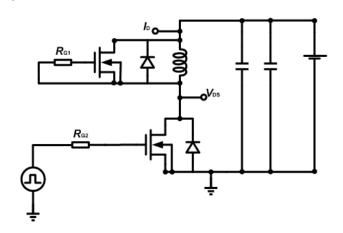


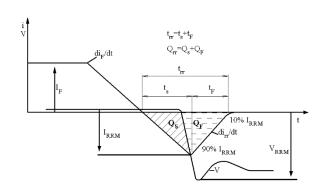




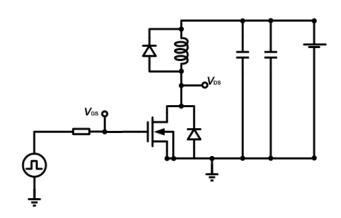
### **5.Test Circuits**

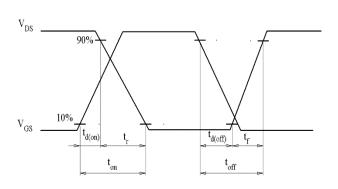
#### 1) Test circuit and waveform for diode characteristics



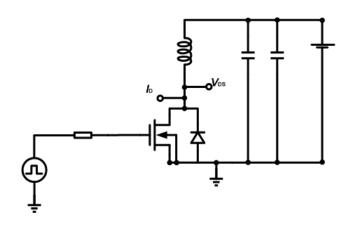


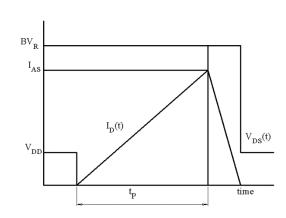
### 2) Switch time test circuit





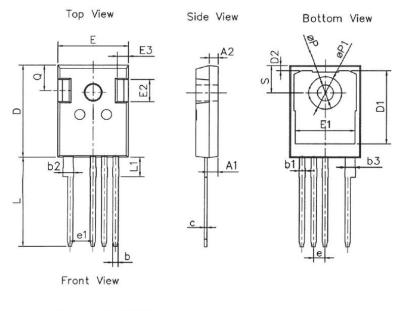
### 3) Unclaimed inductive switching test circuit & waveforms







# 6. Package outline dimensions





	Dimension	unit:[mm]	
SYMBOL	MIN	NOM	MAX
Α	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.85	2.00	2.15
ь	1.11	1.21	1.36
b1	1.11	1.37	1.57
b2	2.24	2.40	2.60
b3	2.11	2.21	2.36
С	0.51	0.60	0.75
D	20.70	20.90	21.30
D1	15.92	16.22	16.52
D2	1.00	1.20	1.35
Е	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
е		2.54 BSC	
e1		5.08 BSC	
L	19.62	19.92	20.22
L1	-	_	4.30
øΡ	3.40	3.60	3.80
øP1	-	-	7.30
Q	5.40	5.80	6.20
S		6.20 BSC	



#### 7. Revision History

Revision	Description	Date
1.0	Initial version	2023/12/15

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